

IEEE HOME | SEARCH IEEE | SHOP | WEB ACCOUNT | CONTACT IEEE


[Membership](#) | [Publications/Services](#) | [Standards](#) | [Conferences](#) | [Careers/Jobs](#)

 Welcome
 United States Patent and Trademark Office


» Advan

[Help](#) | [FAQ](#) | [Terms](#) | [IEEE Peer Review](#)

Quick Links

Welcome to IEEE Xplore®

- ☐ Home
- ☐ What Can I Access?
- ☐ Log-out

Tables of Contents

- ☐ Journals & Magazines
- ☐ Conference Proceedings
- ☐ Standards

Search

- ☐ By Author
- ☐ Basic
- ☐ Advanced

Member Services

- ☐ Join IEEE
- ☐ Establish IEEE Web Account
- ☐ Access the IEEE Member Digital Library

- 1) Enter a single keyword, phrase, or Boolean expression.
Example: acoustic imaging (means the phrase acoustic imaging plus any stem variations)
- 2) Limit your search by using search operators and field codes, if desired.
Example: optical <and> (fiber <or> fibre) <in> ti
- 3) Limit the results by selecting Search Options.
- 4) Click Search. See [Search Examples](#)

```
(plane <near/4>
reconstruction) <sentence>
(curve or circular)
```

Start Search

Clear

Note: This function returns plural and suffixed forms of the keyword(s).

 Search operators: <and> <or> <not> <in> [More](#)

 Field codes: au (author), ti (title), ab (abstract), jn (publication name), de (index term) [More](#)

Search Options:

Select publication types:

- ☒ IEEE Journals
- ☒ IEE Journals
- ☒ IEEE Conference proceedings
- ☒ IEE Conference proceedings
- ☒ IEEE Standards

Select years to search:

 From year: to

Organize search results by:

 Sort by:

 In: order

 List Results per page

[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#) | [Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#) | [No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

Copyright © 2004 IEEE — All rights reserved